

SIC MOSFET

CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2nd generation Silicon Carbide trench technology, the 650 V CoolSiC™ MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

Tab Inlineon 5

PG-LHSOF-4

Features

- Ultra-low switching losses
- Benchmark gate threshold voltage, $V_{GS(th)} = 4.5 \text{ V}$
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

Benefits

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

Potential applications

- SMPS
- Solar PV inverters
- · Energy storage and battery formation
- UPS
- EV charging infrastructure
- Motor drives

Product validation

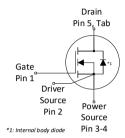
Fully qualified according to JEDEC for Industrial Applications

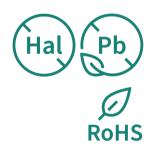
Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction.



Parameter	Value	Unit
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V
$R_{\mathrm{DS(on),typ}}$	50	mΩ
R _{DS(on),max}	62	mΩ
$Q_{G,typ}$	22	nC
$I_{\rm D,pulse}$	113	А
Q _{oss} @ 400 V	42	nC
E _{oss} @ 400 V	5.7	μЈ

Type/Ordering Code	Package	Marking	Related Links
IMTA65R050M2H	PG-LHSOF-4	65R050M2	see Appendix A





Public

CoolSiC™ MOSFET 650 V G2 IMTA65R050M2H



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1 Maximum ratings

at $T_i = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Davamatav	Cymbal		Values			Nieto/Tost Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Continuous DC drain current ¹⁾	I _{DDC}	-	-	43 31	А	$T_c = 25 ^{\circ}\text{C}$ $T_c = 100 ^{\circ}\text{C}$
Peak drain current ²⁾	I _{DM}	-	-	113	А	$T_{\rm c}$ = 25 °C, $V_{\rm GS}$ = 18 V
Avalanche energy, single pulse	E_{AS}	-	-	105	mJ	$I_{\rm D}$ = 3.9 A, $V_{\rm DD}$ = 50 V; see table 11
Avalanche energy, repetitive	E_{AR}	-	-	0.52	mJ	$I_{\rm D}$ = 3.9 A, $V_{\rm DD}$ = 50 V; see table 11
Avalanche current, single pulse	I _{AS}	-	-	3.9	А	-
MOSFET dv/dt ruggedness	dv/dt	-	-	200	V/ns	V _{DS} = 0400 V
Gate source voltage (static) 3)	V_{GS}	-7	-	23	V	-
Gate source voltage (transient)	V_{GS}	-10	-	25	V	t _p ≤ 500 ns, duty cycle ≤ 1 %
Power dissipation	P_{tot}	-	-	197	w	T _c = 25 °C
Storage temperature	$T_{\rm stg}$	-55	-	150	°C	-
Operating junction temperature	T _j	-55	-	175	°C	-
Mounting torque	-	-	-	-	Ncm	-
Continuous reverse drain current ¹⁾	I _{SDC}	-	-	43 31	А	$V_{GS} = 18 \text{ V}, T_c = 25 \text{ °C}$ $V_{GS} = 0 \text{ V}, T_c = 25 \text{ °C}$
Peak reverse drain current ²⁾	I _{SM}	-	-	113 34	А	T_c = 25 °C, t_p ≤ 250 ns T_c = 25 °C
Insulation withstand voltage	V _{ISO}	-	-	n.a.	V	$V_{\rm rms}$, $T_{\rm c}$ = 25 °C, t = 1 min

Limited by $T_{j,max}$.

²⁾ Pulse width $t_{\rm pulse}$ limited by $T_{\rm j,max}$.

³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Cumah al	Values			11	Nata/Tost Condition
	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case	$R_{th(j-c)}$	-	-	0.76	°C/W	Not subject to production test. Parameter verified by design/characterization according to JESD51-14.
Soldering temperature, reflow soldering allowed	$T_{\rm sold}$	-	-	260	°C	reflow MSL1



3 Operating range

Table 4 Operating range

Parameter	Symbol	Values			Unit	Note/ Test Condition
Parameter	Syllibot	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Recommended turn-on voltage	$V_{GS(on)}$	-	18	1	٧	-
Recommended turn-off voltage	$V_{GS(off)}$	-	0	-	V	-



4 Electrical characteristics

at T_i = 25 °C, unless otherwise specified

Table 5 Static characteristics

0

Downwater	Symbol		Values			Nieto/Tost Condition
Parameter	Syllibol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Drain-source voltage	V _{DSS}	650	-	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm D} = 0.37 \text{ mA}$
Gate threshold voltage ⁴⁾	$V_{\rm GS(th)}$	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 3.7 \rm mA$
Zero gate voltage drain current	I _{DSS}	-	1 3	75 -	μΑ	$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25 \text{ °C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175 \text{ °C}$
Gate-source leakage current	I _{GSS}	-	-	100	nA	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	65 50 46 82	- 62 - -	mΩ	$V_{GS} = 15 \text{ V}, I_D = 18.2 \text{ A}, T_j = 25 \text{ °C}$ $V_{GS} = 18 \text{ V}, I_D = 18.2 \text{ A}, T_j = 25 \text{ °C}$ $V_{GS} = 20 \text{ V}, I_D = 18.2 \text{ A}, T_j = 25 \text{ °C}$ $V_{GS} = 18 \text{ V}, I_D = 18.2 \text{ A}, T_j = 175 \text{ °C}$
Internal gate resistance	$R_{G,int}$	-	3.7	-	Ω	<i>f</i> = 1 MHz

⁴⁾ Tested after 1 ms pulse at V_{GS} = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.

Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized. For layout recommendations please use provided application notes or contact Infineon sales office.

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Syllibot	Min.	Тур.	Мах.	Offic	Note/ rest condition
Input capacitance	C _{iss}	-	790	-	pF	$V_{\rm GS} = 0 \text{ V}, V_{\rm DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Reverse transfer capacitance	$C_{\rm rss}$	-	4.7	-	pF	$V_{\rm GS} = 0 \text{ V}, V_{\rm DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output capacitance ⁵⁾	C _{oss}	-	59	77	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output charge ⁵⁾	$Q_{ m oss}$	-	42	55	nC	calculation based on C _{oss}
Effective output capacitance, energy related ⁶⁾	$C_{ m o(er)}$	-	71	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$
Effective output capacitance, time related ⁷⁾	$C_{\rm o(tr)}$	-	105	-	pF	$I_{\rm D}$ = constant, $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 0400 V
Turn-on delay time	$t_{\sf d(on)}$	-	8.1	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 18.2 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Rise time	t _r	-	7.6	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 18.2 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10



Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized. For layout recommendations please use provided application notes or contact Infineon sales office.

Values Symbol **Note/ Test Condition Parameter** Unit Min. Typ. Max. $V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ Turn-off delay time 13.5 ns $I_{\rm D} = 18.2 \, \text{A}, \, R_{\rm G.ext} = 1.8 \, \Omega;$ $t_{\rm d(off)}$ see table 10 $V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ Fall time 4.4 $t_{\scriptscriptstyle \mathrm{f}}$ ns $I_{\rm D} = 18.2 \, \text{A}, \, R_{\rm G.ext} = 1.8 \, \Omega;$ see table 10 $V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ Turn-ON switching losses 8) E_{on} 24 μJ $I_{\rm D} = 18.2 \, \text{A}, \, R_{\rm G,ext} = 1.8 \, \Omega$ $V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ Turn-OFF switching losses 8) E_{off} 10 μJ $I_{\rm D}$ = 18.2 A, $R_{\rm G,ext}$ = 1.8 Ω $V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$

34

иJ

 $I_{\rm D}$ = 18.2 A, $R_{\rm G,ext}$ = 1.8 Ω

 E_{tot}

Table 7 Gate charge characteristics

Total switching losses 8)

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Syllibot	Min.	Тур.	Мах.	Oilit	Note/ Test Condition
Plateau gate to source charge	$Q_{GS(pl)}$	-	5.6	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm D} = 18.2 \text{ A},$ $V_{\rm GS} = 0 \text{ to } 18 \text{ V}$
Gate to drain charge	Q_{GD}	-	4.3	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm D} = 18.2 \text{ A},$ $V_{\rm GS} = 0 \text{ to } 18 \text{ V}$
Total gate charge	Q_{G}	-	22	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm D} = 18.2 \text{ A},$ $V_{\rm GS} = 0 \text{ to } 18 \text{ V}$

Table 8 Reverse diode characteristics

Davamatar	Symbol	Values			Linit	Note/ Test Condition
Parameter		Min.	Тур.	Мах.	Unit	Note/ Test Condition
Drain-source reverse voltage	$V_{\rm SD}$	-	4.3	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm S} = 18.2 \text{ A}, T_{\rm j} = 25 \text{ °C}$
MOSFET forward recovery time	t _{fr}	-	10.4 6.1	-	ns	$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 1000 \text{A/\mu s}; \text{see table 9}$ $V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 4000 \text{A/\mu s}; \text{see table 9}$

⁵⁾ Maximum specification is defined by calculated six sigma upper confidence bound

 $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.

⁷⁾ $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V.

⁸⁾ Values for 4-pin configuration based on TO-263-7 measurements; MOSFET used in half-bridge configuration without external diode



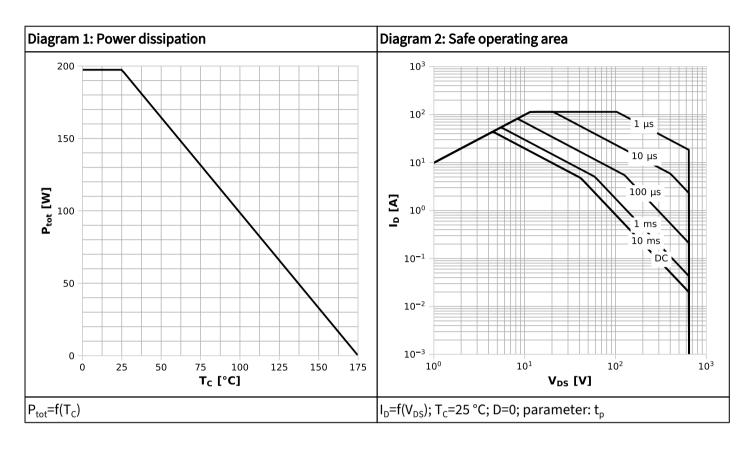
Table 8 Reverse diode characteristics

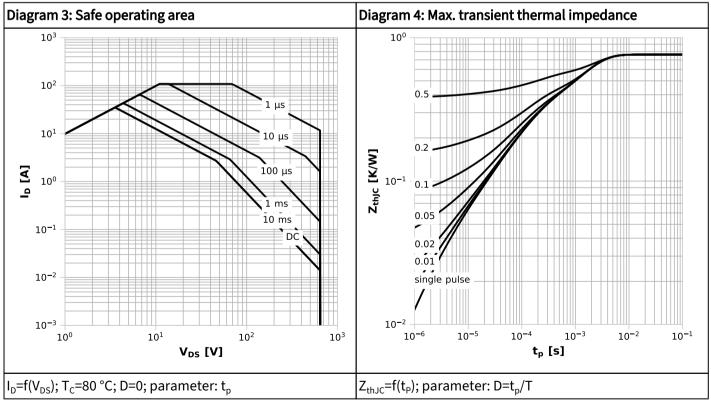
Davamatav	Cumahal	Values			l lmit	Nicto/Tost Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
MOSFET forward recovery charge ⁹⁾	$Q_{ m fr}$	-	44 62	-	nC	$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 1000 \text{A/\mu s}; \text{see table 9}$ $V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 4000 \text{A/\mu s}; \text{see table 9}$
MOSFET peak forward recovery current	I_{frm}	-	8.5 20.4	-	A	$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 1000 \text{A/\mu s}; \text{see table 9}$ $V_{\rm DD} = 400 \text{V}, I_{\rm S} = 18.2 \text{A},$ $di_{\rm S}/dt = 4000 \text{A/\mu s}; \text{see table 9}$

⁹⁾ Q_{fr} includes Q_{oss}

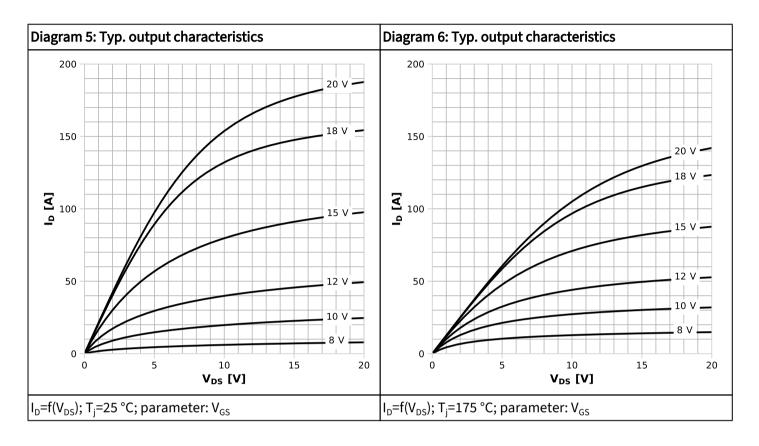


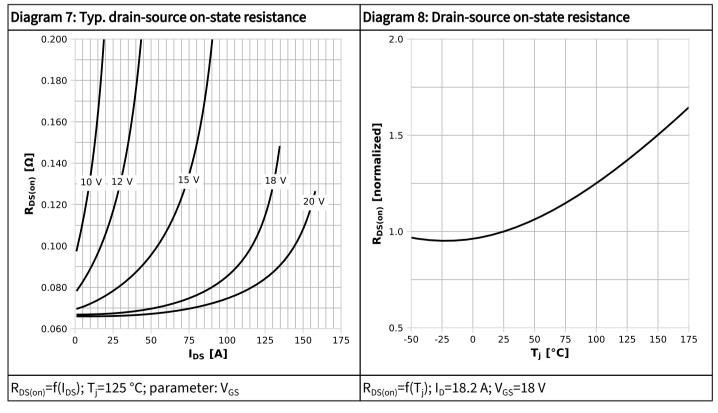
5 Electrical characteristics diagrams



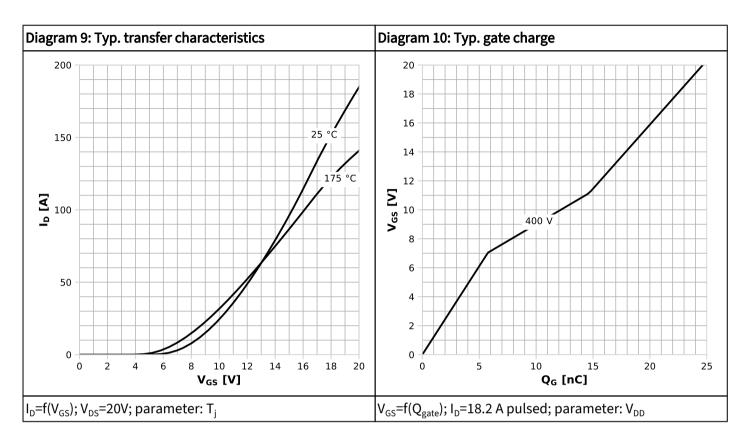


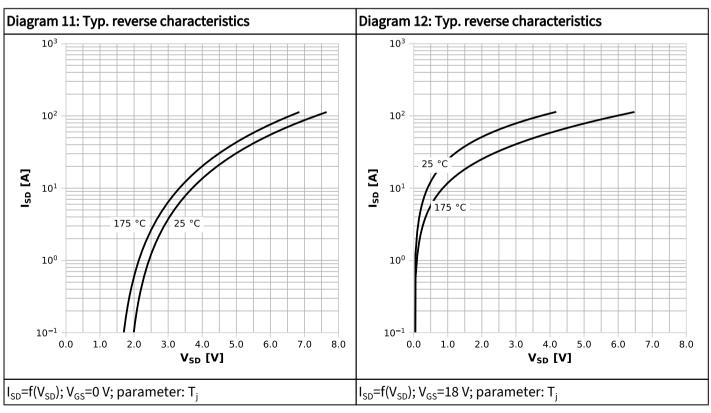




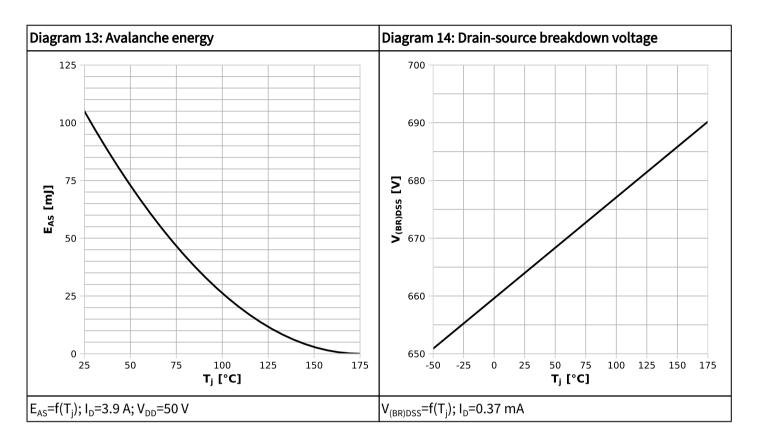


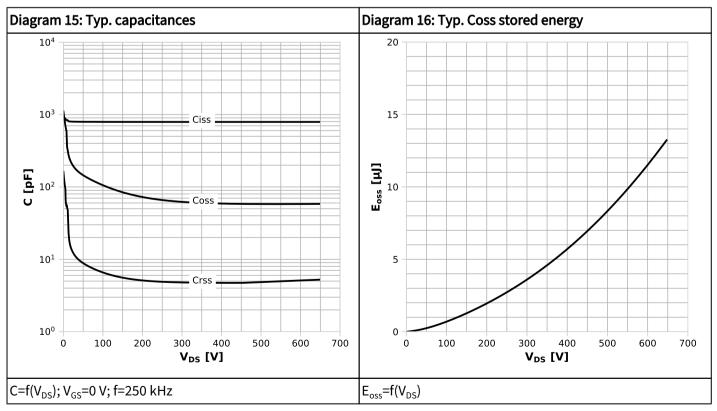




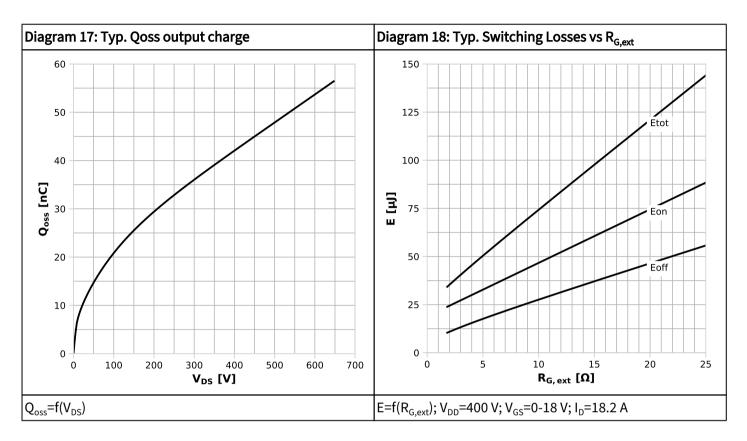


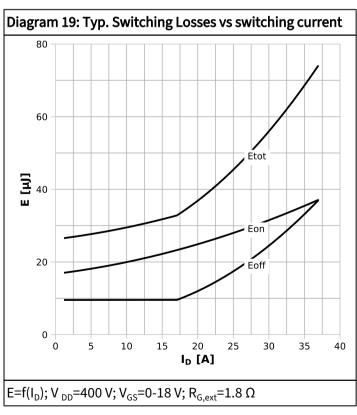














6 Test Circuits

Table 9 Body diode characteristics (CoolSiC)

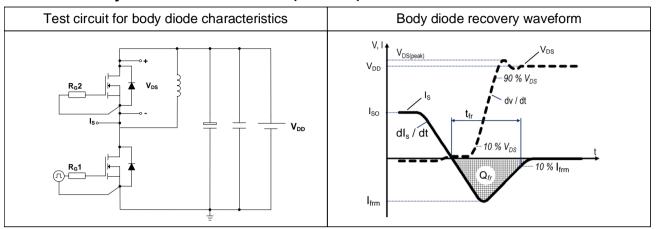


Table 10 Switching times (CoolSiC)

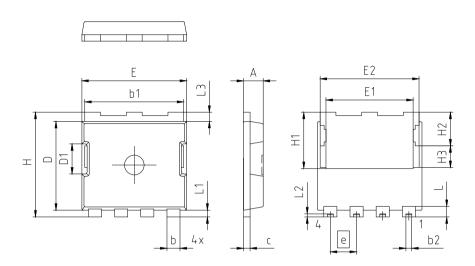


Table 11 Unclamped inductive load





7 Package Outlines



PACKAGE - GROUP NUMBER:	PG-LHS	OF-4-U01					
DIMENSIONS	MILLIN	METERS					
DIMENSIONS	MIN.	MAX.					
Α	1.40	1.60					
b	0.90	1.10					
b1	7.46	7.66					
b2	0.42	0.50					
С	0.40	0.60					
D	6.59	6.99					
D1	2	2.30					
E	7.80	8.20					
E1	6	6.66					
E2	7.56						
е	2	.00					
N		4					
Н	7.80	8.20					
H1	4	.30					
H2	2	.57					
Н3	1	.65					
L	0.50 1.00						
L1	0.51						
L2	0	.23					
L3	0.50	0.90					

Figure 1 Outline PG-LHSOF-4, dimensions in mm



8 Appendix A

Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Webpage
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Application Note
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Simulation Model
- IFX Design tools



Revision History

IMTA65R050M2H

Revision 2024-05-13, Rev. 2.1

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2024-04-19	Release of final
2.1	2024-05-13	Updated diagram axis max. and min. values.

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